

## Characterization of Thermal Effects on Microwave Transistor Performance Using an Efficient Physical Model

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*J.S. Atherton, C.M. Snowden and J.R. Richardson. "Characterization of Thermal Effects on Microwave Transistor Performance Using an Efficient Physical Model." 1993 MTT-S International Microwave Symposium Digest 93.3 (1993 Vol. III [MWSYM]): 1181-1184.*

A physical model is described which is capable of predicting the effects of self-heating on MESFET performance whilst being efficient enough to run on a personal computer. Comparisons with the true DC characteristics for a number of devices of different gate lengths and microwave measurements demonstrates the validity of the model.

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